



Agilent Technologies' New Modular PXI Voltage/Current Source Solution Reduces Test Time

Agilent Technologies Inc. today introduced the Agilent M9186A PXI isolated single-channel voltage/current source, a modular voltage-current source for use in automotive electronics test applications.

The modular PXI-based solution enables testers to generate a voltage and measurement of the resultant current, or generate a current and measurement of the resultant voltage. The M9186A comes with SENSE input to supply accurate voltage to the device under test (DUT). The module also offers a safety interlock feature to protect the DUT from potential damage from high voltages.



"Customers will benefit from the ease of use of this solution," said Daniel Mak, Agilent vice president and general manager, Measurement Systems Division. "Agilent includes sample codes that end-users can easily modify. This simplifies the process of integrating the module into a measurement system and reduces the amount of time it takes to complete complex tasks."

Additional information is available at www.agilent.com/find/M9186A. For more information on Agilent's automotive and board functional test solutions, visit www.agilent.com/find/automotive.

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Agilent Technologies' New Nanoindentation Technique Enables Substrate-Independent Measurements on Thin Film Materials

Agilent Technologies Inc. today announced an innovative nanoindentation technique available exclusively on the Agilent Nano Indenter G200 instrumentation platform. The new technique gives researchers the unprecedented ability to make substrate-independent measurements on thin film materials quickly, easily and confidently by means of nanoindentation. It is ideal for evaluating the elastic modulus of hard samples on soft substrates, or of soft samples on hard substrates.

Substrate influence is a common problem when using nanoindentation to evaluate the elastic modulus of thin film materials. The technique is able to extract the film modulus from the measured substrate-affected modulus, assuming that the film thickness and substrate modulus are known. The technique is applicable to a variety of film-substrate systems.

Agilent's Jennifer Hay will present an overview of the technique at a special reception during Materials Research Society (MRS) in Boston on Nov. 30. Field luminary Warren Oliver will introduce Ms. Hay at the event.

As the world's most accurate,



flexible and user-friendly instrument for nanoscale mechanical testing, the G200 utilizes electromagnetic actuation to achieve unparalleled dynamic range in force and displacement. The G200 enables measurement of Young's modulus and hardness in compliance with ISO 14577, as well as measurement of deformation over six orders of magnitude – from nanometers to millimeters.

Nanomechanical Systems from Agilent Technologies

Agilent Technologies offers high-precision, modular nanomeasurement solutions for research, industry and education. Exceptional worldwide support is provided by experienced application scientists and technical service personnel. Agilent's leading-edge R&D laboratories ensure the timely introduction and optimization of innovative and easy-to-use nanomechanical system technologies.

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